



ALPHA & OMEGA
SEMICONDUCTOR

AON2705
30V P-Channel MOSFET
with Schottky Diode

General Description

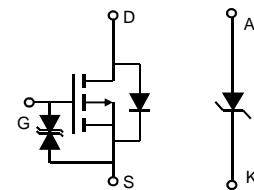
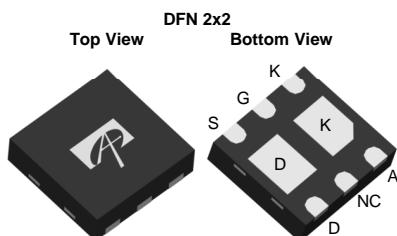
The AON2705 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. A Schottky diode is provided to facilitate the implementation of a bidirectional blocking switch, or for DC-DC conversion applications.

Product Summary

V_{DS}	-30V
I_D (at $V_{GS}=-10V$)	-3.0A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 108mΩ
$R_{DS(ON)}$ (at $V_{GS} = -4.5V$)	< 165mΩ

Typical ESD protection

HBM Class 3A
V_{KA}
I_F
V_F (at $I_F=1A$)



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	MOSFET	Schottky	Units
Drain-Source Voltage	V_{DS}	-30		V
Gate-Source Voltage	V_{GS}	± 20		V
Continuous Drain Current ^A	I_D	-3		A
$T_A=70^\circ C$		-2.4		
Pulsed Drain Current ^B	I_{DM}	-16		
Schottky reverse voltage	V_{KA}		20	V
Continuous Forward Current ^A	I_F		2.5	A
$T_A=70^\circ C$			1.5	
Pulsed Forward Current ^B	I_{FM}		15	
Power Dissipation ^A	P_D	1.5	1.45	W
$T_A=70^\circ C$		0.95	0.92	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	°C

Thermal Characteristics

Parameter: MOSFET	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	35	45	°C/W
Maximum Junction-to-Ambient ^A		65	85	°C/W
Parameter: Schottky				
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	36	47	°C/W
Maximum Junction-to-Ambient ^A		67	87	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS} = \pm 16\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.3	-1.8	-2.3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-16			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-3\text{A}$ $T_J=125^\circ\text{C}$	89	108		$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-2.5\text{A}$	123	150	132	
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-3\text{A}$	6			S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-0.8	-1		V
I_S	Maximum Body-Diode Continuous Current				-1.25	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		180		pF
C_{oss}	Output Capacitance		44			pF
C_{rss}	Reverse Transfer Capacitance		25			pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	18.5	37		Ω
SWITCHING PARAMETERS						
$Q_{g(10\text{V})}$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-3\text{A}$		4	6	nC
$Q_{g(4.5\text{V})}$	Total Gate Charge		2	3.5		nC
Q_{gs}	Gate Source Charge		0.6			nC
Q_{gd}	Gate Drain Charge		1			nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=5\Omega, R_{\text{GEN}}=3\Omega$	8			ns
t_r	Turn-On Rise Time		5			ns
$t_{D(\text{off})}$	Turn-Off DelayTime		18			ns
t_f	Turn-Off Fall Time		7			ns
t_{rr}	Body Diode Reverse Recovery Time		10.5			ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-3\text{A}, dI/dt=100\text{A}/\mu\text{s}$	3.5			nC
SCHOTTKY PARAMETERS						
V_F	Forward Voltage Drop	$I_F=1\text{A}$	0.4	0.45		V
I_{rm}	Maximum reverse leakage current	$V_R=5\text{V}$		0.05		mA
		$V_R=5\text{V}, T_J=125^\circ\text{C}$		10		
I_{rm}	Maximum reverse leakage current	$V_R=16\text{V}$		0.1		mA
		$V_R=16\text{V}, T_J=125^\circ\text{C}$		20		
C_T	Junction Capacitance	$V_R=10\text{V}$	34			pF
t_{rr}	Schottky Reverse Recovery Time	$I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$	11	14		ns
Q_{rr}	Schottky Reverse Recovery Charge	$I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$	0.8			nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

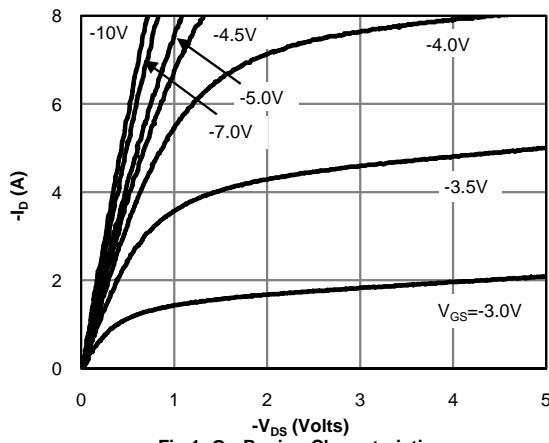
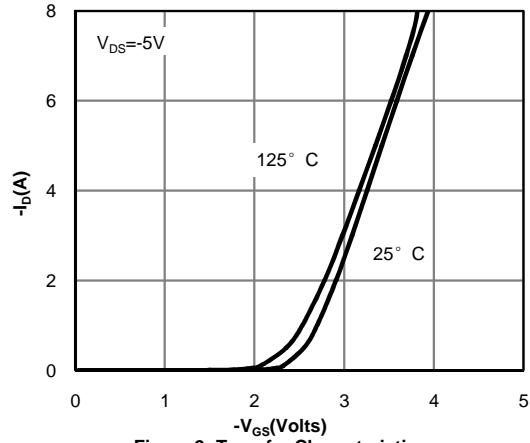
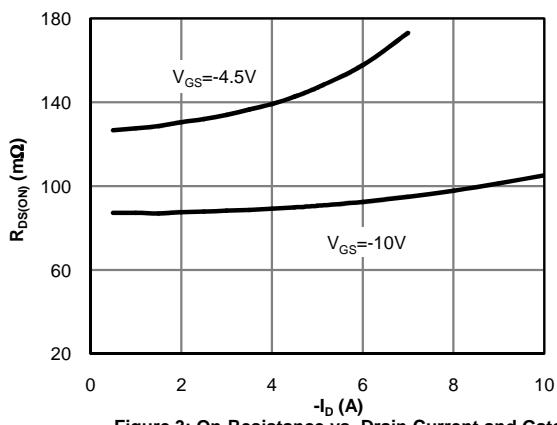
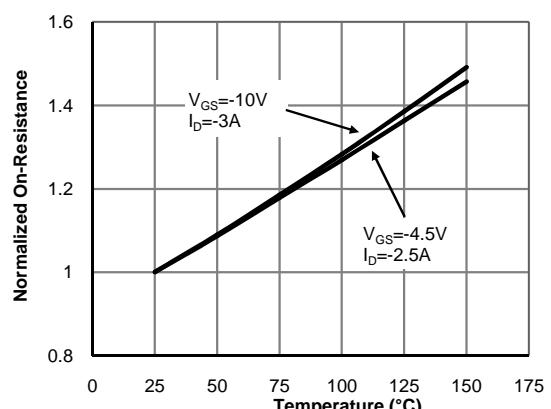
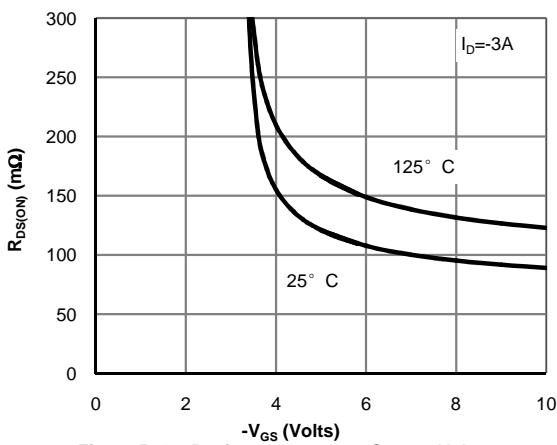
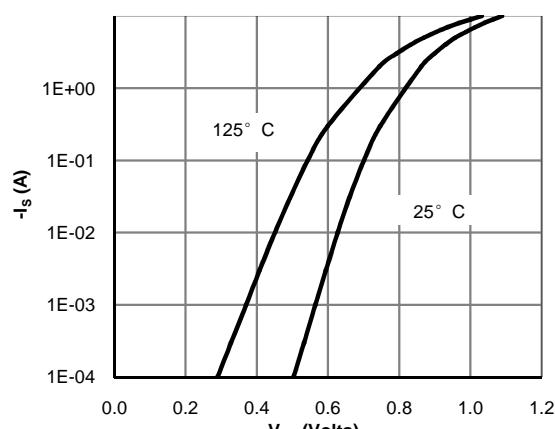
B: Repetitive rating, pulse width limited by junction temperature.

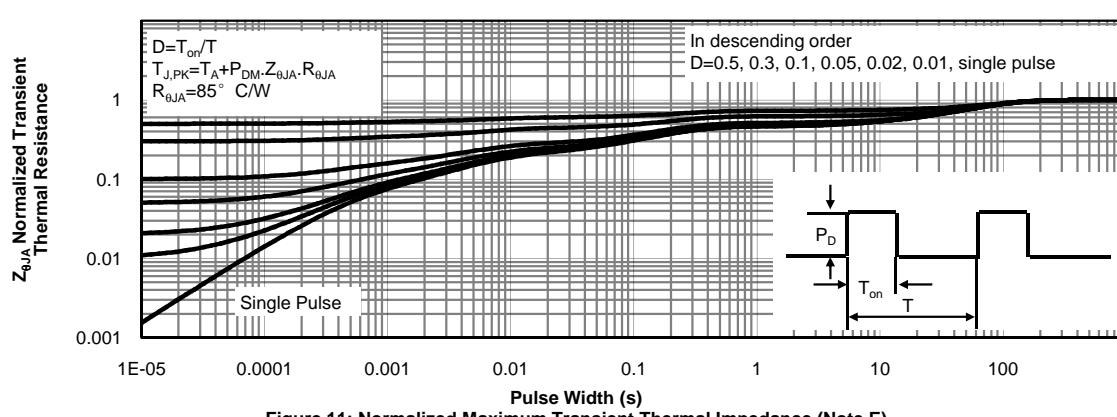
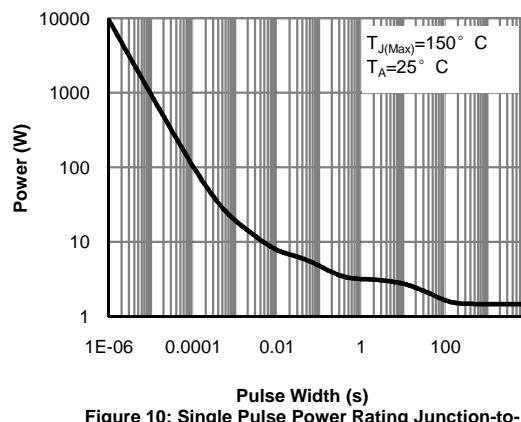
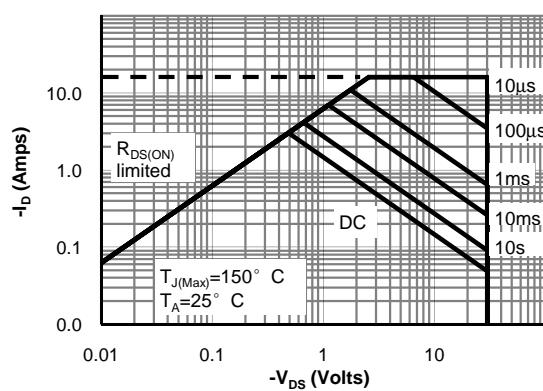
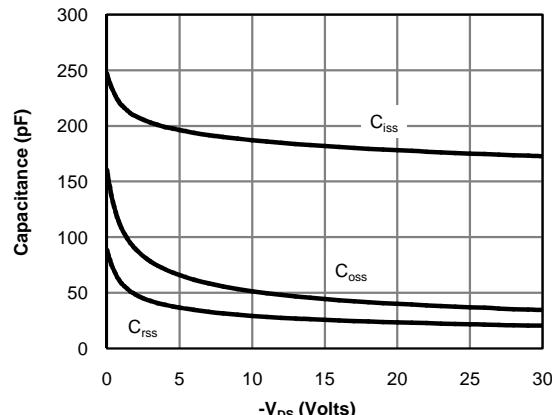
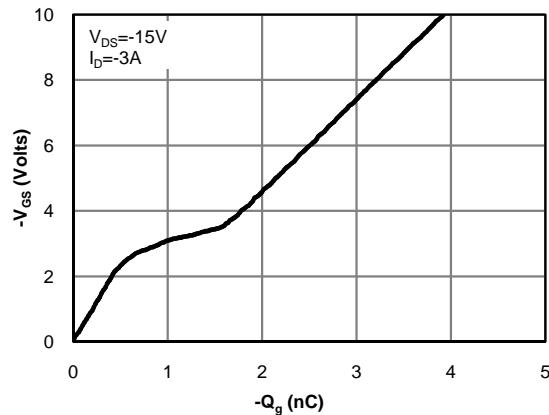
C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

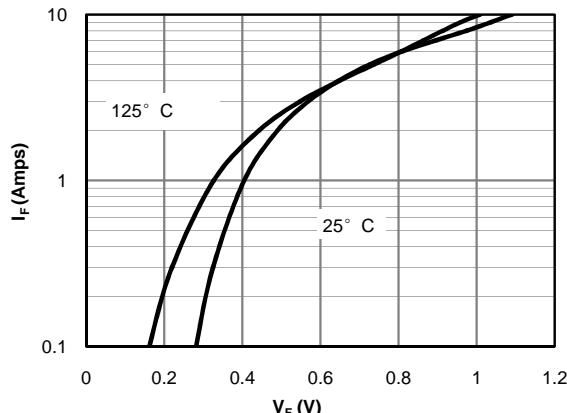
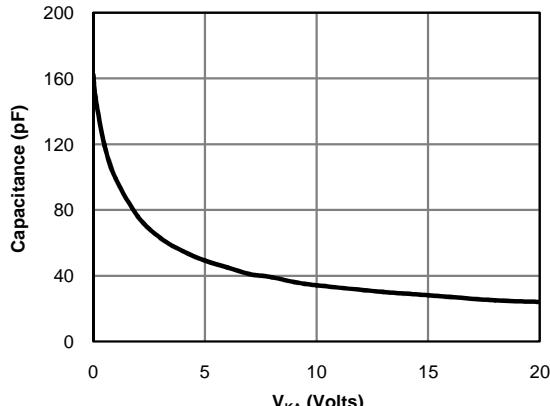
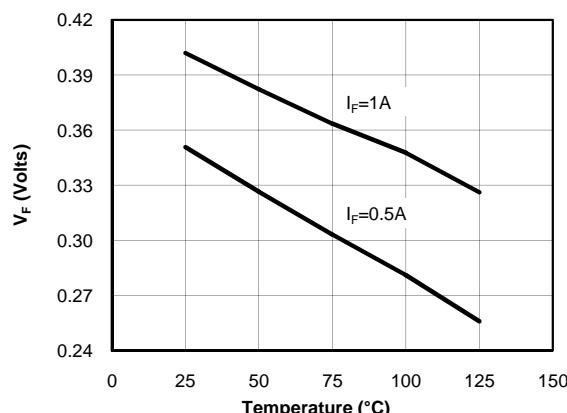
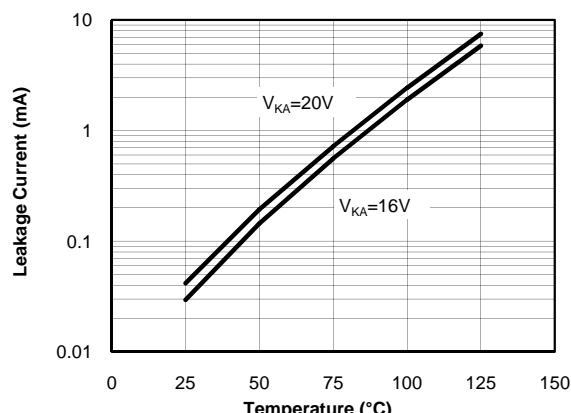
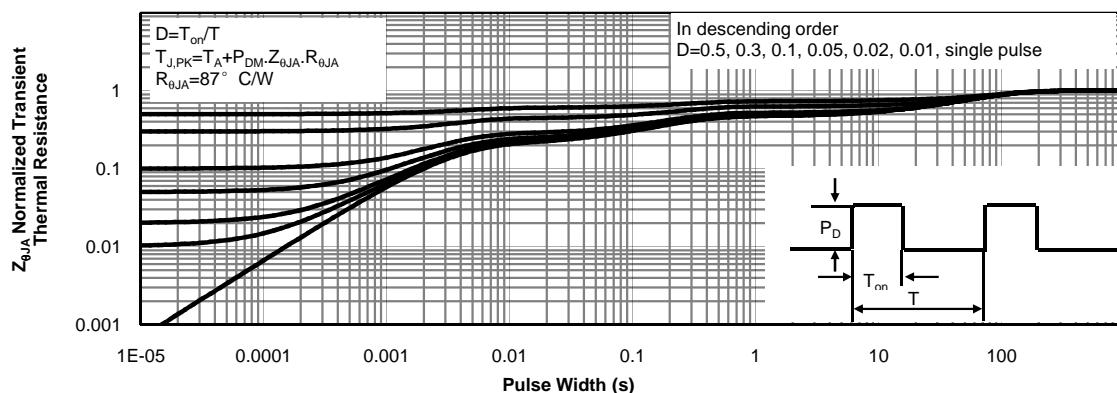
D: The static characteristics in Figures 1 to 6 are obtained using <300 ms pulses, duty cycle 0.5% max.

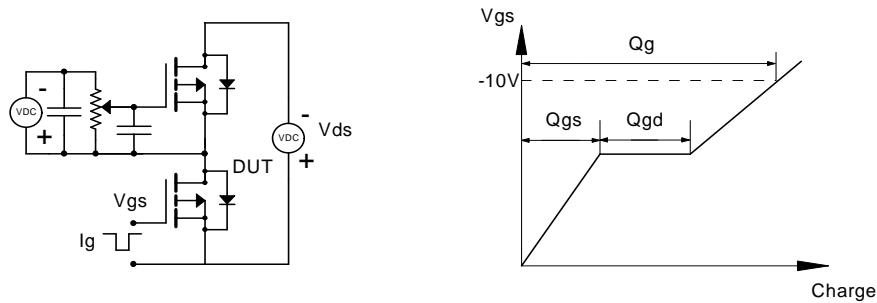
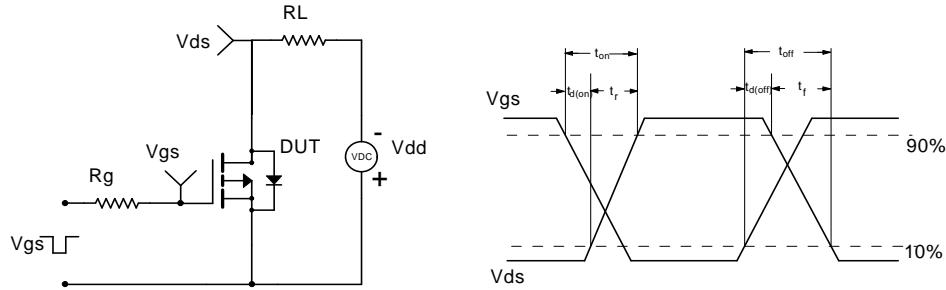
E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Drain Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


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Figure 12: Schottky Forward Characteristics

Figure 13: Schottky Capacitance Characteristics

Figure 14: Schottky Forward Drop vs. Junction Temperature

Figure 15: Schottky Leakage Current vs. Junction Temperature

Figure 16: Schottky Normalized Maximum Transient Thermal Impedance (Note E)


Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
